Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/810,366	FIEDLER, LEE	
Examiner	Art Unit	
SANG KIM	3654	

SEARCHED				
Class	Subclass	Date	Examiner	
242	530.1	1/31/2006	SK	
242	533.4	1/31/2006	SK	
242	535.4	1/31/2006	SK	
242	532.2	1/31/2006	SK	
242	547	1/31/2006	SK	
242	548	1/31/2006	SK	
242	532	1/31/2006	SK	
242	532.7	1/31/2006	SK	
of dufet	А	4-28-06	5K	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
attached	<b>/</b>	4-18-06	5K	
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
John Nguyen: 242/530.1, 533.4, 535.4, 532.2, 547, 548, 532, 532.7	1/30/2006	SK
Kathy Matecki: Text Search	2/3/2006	SK